


<b>Search Notes</b> 	<b>Application/Control No.</b> 10523622	<b>Applicant(s)/Patent Under Reexamination</b> LIU ET AL.
	<b>Examiner</b> Nikki H Dees	<b>Art Unit</b> 1794

SEARCHED			
Class	Subclass	Date	Examiner
426	656, 802	10/22/2007	nhd
530	378	10/22/2007	nhd

SEARCH NOTES		
Search Notes	Date	Examiner
EAST search history attached	10/22/2007	nhd
Inventor search in eDAN	10/22/2007	nhd
Updated EAST search history attached	05/08/2008	nhd
Updated inventor search in eDAN	05/08/2008	nhd
Updated EAST search history attached	8/22/2008	nhd
Updated inventor search in eDAN	8/22/2008	nhd

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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